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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10063869	05/21/2002	324	75	2858	TRUNG NGUYEN

**APPLICANTS: Araki Chihiro:

**CONTINUING DATA VERIFIED:

None

** FOREIGN APPLICATIONS VERIFIED:

JAPAN 2001-161739 05/30/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	ATTORNEY DOCKET NO
Foreign priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no			SIMTEK6349
35 USC 119 conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no			
Verified and Acknowledged Examiners's initials			

TITLE : Inspection method and inspection apparatus for semiconductor circuit

U.S. DEPT. OF COM. PAT. & TM. PTO 4161 Rev. 12-94

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G.
ISSUE FEE		Primary Examiner	DRAWING	
Amount Due	Date Paid		Sheets Drwg.	Figs. Drwg.
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	Application Examiner	
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